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- Low  $r_{DS(on)} \dots 1.3 \Omega$  Typical
- Avalanche Energy . . . 75 mJ
- Eight Power DMOS Transistor Outputs of 250-mA Continuous Current
- 1.5-A Pulsed Current Per Output
- Output Clamp Voltage at 45 V
- Devices Are Cascadable
- Low Power Consumption

### description

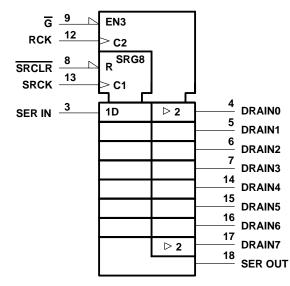
The TPIC6595 is a monolithic, high-voltage, highcurrent power 8-bit shift register designed for use in systems that require relatively high load power. The device contains a built-in voltage clamp on the outputs for inductive transient protection. Power driver applications include relays, solenoids, and other medium-current or high-voltage loads.

This device contains an 8-bit serial-in, parallel-out shift register that feeds an 8-bit D-type storage register. Data transfers through both the shift and storage registers on the rising edge of the shift-register clock (SRCK) and the register clock (RCK) respectively. The storage register transfers data to the output buffer when shiftregister clear (SRCLR) is high. When SRCLR is low, the input shift register is cleared. When output enable ( $\overline{G}$ ) is held high, all data in the output buffers is held low and all drain outputs are off. When  $\overline{\mathbf{G}}$  is held low, data from the storage register is transparent to the output buffers. The serial output (SER OUT) allows for cascading of the data from the shift register to additional devices.

Outputs are low-side, open-drain DMOS transistors with output ratings of 45 V and 250-mA

DW OR N PACKAGE (TOP VIEW)							
PGND V <sub>CC</sub> SER IN DRAIN0 DRAIN1 DRAIN2 DRAIN2 DRAIN3 G G PGND	1 2 3 4 5 6 7 8 9 10	20 19 18 17 16 15 14 13 12 11	PGND LGND SER OUT DRAIN7 DRAIN6 DRAIN5 DRAIN4 SRCK RCK PGND				

### logic symbol<sup>†</sup>



<sup>†</sup> This symbol is in accordance with ANSI/IEEE Std 91-1984 and IEC Publication 617-12.

continuous sink current capability. When data in the output buffers is low, the DMOS-transistor outputs are off. When data is high, the DMOS-transistor outputs have sink current capability.

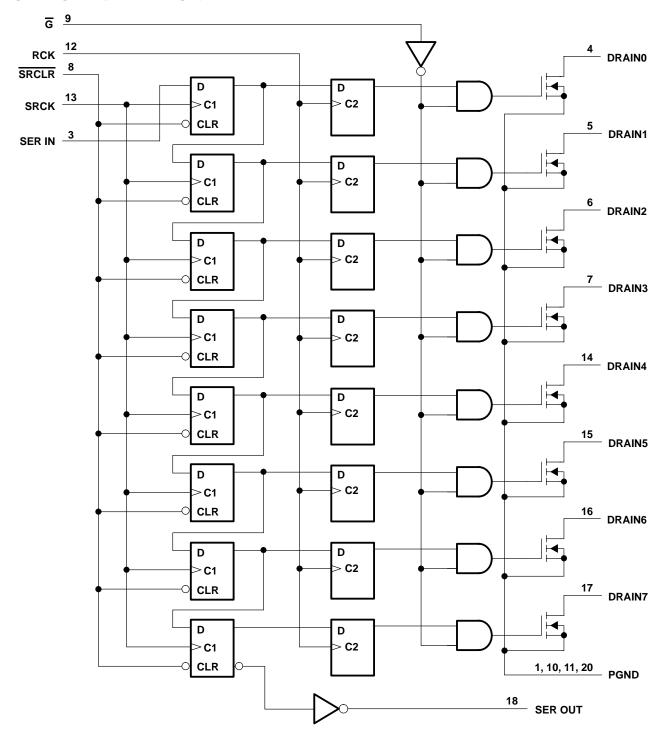
Separate power and logic level ground pins are provided to facilitate maximum system flexibility. Pins 1, 10, 11, and 20 are internally connected, and each pin must be externally connected to the power system ground in order to minimize parasitic inductance. A single-point connection between pin 19, logic ground (LGND), and pins 1, 10, 11, and 20, power grounds (PGND), must be externally made in a manner that reduces crosstalk between the logic and load circuits.

The TPIC6595 is characterized for operation over the operating case temperature range of -40°C to 125°C.



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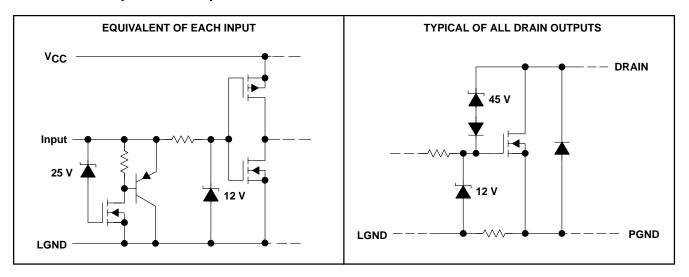
### logic diagram (positive logic)





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### schematic of inputs and outputs



# absolute maximum ratings over recommended operating case temperature range (unless otherwise noted)<sup>†</sup>

Logic supply voltage, V <sub>CC</sub> (see Note 1)	
Logic input voltage range, V <sub>I</sub>	
Power DMOS drain-to-source voltage, V <sub>DS</sub> (see Note 2)	
Continuous source-drain diode anode current	
Pulsed source-drain diode anode current	
Pulsed drain current, each output, all outputs on, $I_{Dn}$ , $T_A = 25^{\circ}C$ (see Note 3)	750 mA
Continuous drain current, each output, all outputs on, IDn, TA = 25°C	
Peak drain current single output, I <sub>DM</sub> , T <sub>A</sub> = 25°C (see Note 3)	
Single-pulse avalanche energy, E <sub>AS</sub> (see Note 4)	
Avalanche current, I <sub>AS</sub> (see Note 4)	1 A
Continuous total power dissipation	See Dissipation Rating Table
Operating virtual junction temperature range, T <sub>1</sub>	
Storage temperature range, T <sub>stg</sub>	
Lead temperature 1,6 mm (1/16 inch) from case for 10 seconds	260°C

<sup>†</sup> Stresses beyond those listed under "absolute maximum ratings" may cause permanent damage to the device. These are stress ratings only and functional operation of the device at these or any other conditions beyond those indicated under "recommended operating conditions" is not implied. Exposure to absolute-maximum-rated conditions for extended periods may affect device reliability.

NOTES: 1. All voltage values are with respect to LGND and PGND.

- 2. Each power DMOS source is internally connected to PGND.
- 3. Pulse duration  $\leq$  100 µs, duty cycle  $\leq$  2 %

4. DRAIN supply voltage = 15 V, starting junction temperature (T<sub>JS</sub>) =  $25^{\circ}$ C, L = 100 mH, I<sub>AS</sub> = 1 A (see Figure 4).

#### **DISSIPATION RATING TABLE**

PACKAGE	T <sub>A</sub> ≤ 25°C POWER RATING	DERATING FACTOR ABOVE T <sub>A</sub> = 25°C	T <sub>A</sub> = 125°C POWER RATING
DW	1125 mW	9.0 mW/°C	225 mW
Ν	1150 mW	9.2 mW/°C	230 mW



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# recommended operating conditions over recommended operating temperature range (unless otherwise noted)

	MIN	MAX	UNIT
Logic supply voltage, V <sub>CC</sub>	4.5	5.5	V
High-level input voltage, VIH	0.85 V <sub>CC</sub>		V
Low-level input voltage, VIL		0.15 V <sub>CC</sub>	V
Pulsed drain output current, $T_C = 25^{\circ}C$ , $V_{CC} = 5 V$ (see Notes 3 and 5)	-1.8	1.5	А
Setup time, SER IN high before SRCK <sup>↑</sup> , t <sub>SU</sub> (see Figure 2)	10		ns
Hold time, SER IN high after SRCK <sup>↑</sup> , t <sub>h</sub> (see Figure 2)	10		ns
Pulse duration, t <sub>w</sub> (see Figure 2)	20		ns
Operating case temperature, T <sub>C</sub>	-40	125	°C

### electrical characteristics, $V_{CC}$ = 5 V, $T_C$ = 25°C (unless otherwise noted)

	PARAMETER		TEST COND	TIONS	MIN	TYP	MAX	UNIT
V <sub>(BR)</sub> DSX	Drain-source breakdown voltage	I <sub>D</sub> = 1 mA			45			V
V <sub>SD</sub>	Source-drain diode forward voltage	I <sub>F</sub> = 250 mA,	See Note 3			0.85	1	V
Maria	High-level output voltage,	$I_{OH} = -20 \text{ mA}$	$V_{\rm CC} = 4.5  \rm V$		4.4	4.49		V
<sup>V</sup> ОН	SER OUT	$I_{OH} = -4 \text{ mA},$	$V_{CC}$ = 4.5 V		4.1	4.3		v
Val	Low-level output voltage, SER	I <sub>OH</sub> = 20 mA,	I <sub>OH</sub> = 20 mA, V <sub>CC</sub> = 4.5 V			0.002	0.1	V
VOL	OUT	I <sub>OH</sub> = 4 mA,	$V_{CC}$ = 4.5 V			0.2	0.4	v
V <sub>(hys)</sub>	Input hysteresis	V <sub>DS</sub> = 15 V				1.3		V
IIH	High-level input current	$V_{CC} = 5.5 V,$	$V_{I} = V_{CC}$				1	μA
١ <sub>IL</sub>	Low-level input current	V <sub>CC</sub> = 5.5 V,	V <sub>I</sub> = 0				-1	μA
ICCL	Logic supply current	IO = 0,	All inputs low			15	100	μA
ICC(FRQ)	Logic supply current frequency	$f_{SRCK} = 5 \text{ MHz}, I_O = 0, C_L = 30 \text{ pF},$ See Figures 1, 2, and 6			0.6	5	mA	
۱ <sub>N</sub>	Nominal current	$V_{DS(on)} = 0.5$ $I_N = I_D$ ,	V, T <sub>C</sub> = 85°C	See Notes 5, 6, and 7		250		mA
la eu	Off state drain surrant	V <sub>DS</sub> = 40 V			0.05	1	A	
IDSX	Off-state drain current	V <sub>DS</sub> = 40 V,	T <sub>C</sub> = 125°C			0.15	5	μA
		I <sub>D</sub> = 250 mA,	$V_{CC}$ = 4.5 V			1.3	2	
<sup>r</sup> DS(on)	Static drain-source on-state resistance	I <sub>D</sub> = 250 mA, V <sub>CC</sub> = 4.5 V	T <sub>C</sub> = 125°C,	See Notes 5 and 6 and Figures 9 and 10		2	3.2	Ω
		I <sub>D</sub> = 500 mA,	V <sub>CC</sub> = 4.5 V			1.3	2	

### switching characteristics, V<sub>CC</sub> = 5 V, T<sub>C</sub> = 25°C

PARAMETER		TEST CONDITIONS	MIN	TYP	MAX	UNIT
<sup>t</sup> PLH	Propagation delay time, low-to-high-level output from $\overline{G}$			650		ns
<sup>t</sup> PHL	Propagation delay time, high-to-low-level output from $\overline{G}$	C <sub>L</sub> = 30 pF, I <sub>D</sub> = 250 mA,		150		ns
t <sub>r</sub>	Rise time, drain output	See Figures 1 and 2		750		ns
t <sub>f</sub>	Fall time, drain output			425		ns
ta	Reverse-recovery-current rise time	I <sub>F</sub> = 250 mA, di/dt = 20 A/μs,		100		
t <sub>rr</sub>	Reverse-recovery time	See Notes 5 and 6 and Figure 3		300		ns

NOTES: 3. Pulse duration  $\leq 100 \ \mu$ s, duty cycle  $\leq 2\%$ 

5. Technique should limit  $T_J - T_C$  to 10°C maximum.

6. These parameters are measured with voltage-sensing contacts separate from the current-carrying contacts.

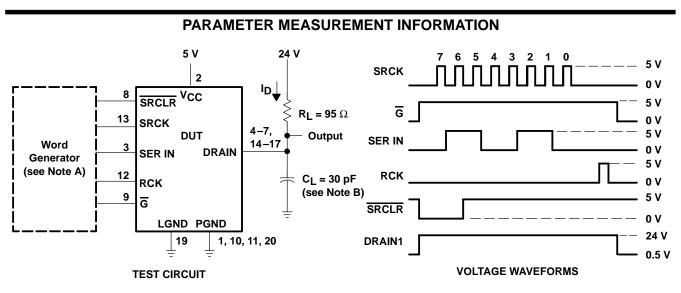
7. Nominal current is defined for a consistent comparison between devices from different sources. It is the current that produces a voltage drop of 0.5 V at  $T_C = 85^{\circ}C$ .



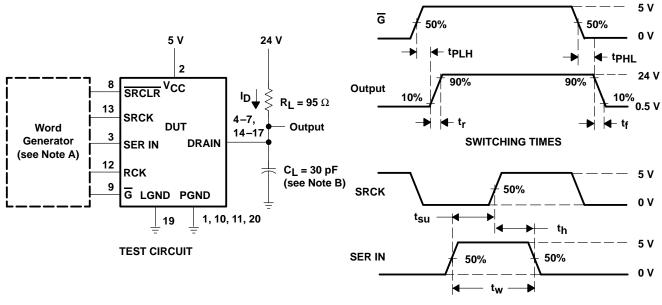
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#### thermal resistance

PARAMETER		TEST CONDITIONS	MIN	MAX	UNIT	
$R_{\theta JA}$ Thermal resistance,	Thermal registered junction to embient	DW package	All 8 outputs with equal power		111	°C/W
	Thermal resistance, junction-to-ambient	N package	All 8 outputs with equal power		108	







INPUT SETUP AND HOLD WAVEFORMS

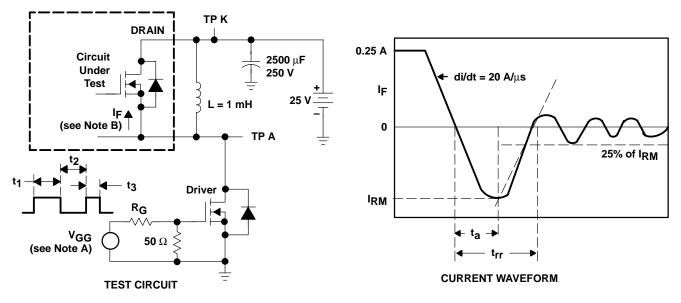


NOTES: A. Outputs DRAIN 1, 2, 5, and 6 low (PGND), all other DRAIN outputs are at 24 V. The word generator has the following characteristics:  $t_f \le 10$  ns,  $t_f \le 10$  ns,  $t_W = 300$  ns, pulsed repetition rate (PRR) = 5 kHz,  $Z_O = 50 \Omega$ .

B.  $\ C_L$  includes probe and jig capacitance.



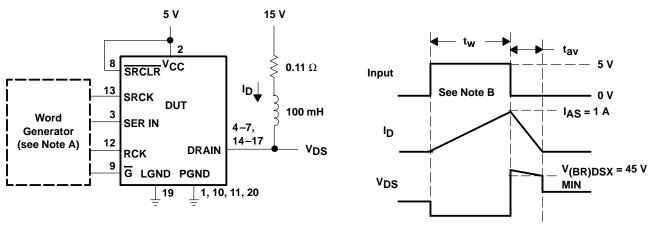
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### PARAMETER MEASUREMENT INFORMATION

- NOTES: A. The V<sub>GG</sub> amplitude and R<sub>G</sub> are adjusted for di/dt = 20 A/ $\mu$ s. A V<sub>GG</sub> double-pulse train is used to set I<sub>F</sub> = 0.25 A, where t<sub>1</sub> = 10  $\mu$ s, t<sub>2</sub> = 7  $\mu$ s, and t<sub>3</sub> = 3  $\mu$ s.
  - B. The DRAIN terminal under test is connected to the TP K test point. All other terminals are connected together and connected to the TP A test point.

#### Figure 3. Reverse-Recovery-Current Test Circuit and Waveforms of Source-Drain Diode



#### SINGLE-PULSE AVALANCHE ENERGY TEST CIRCUIT

VOLTAGE AND CURRENT WAVEFORMS

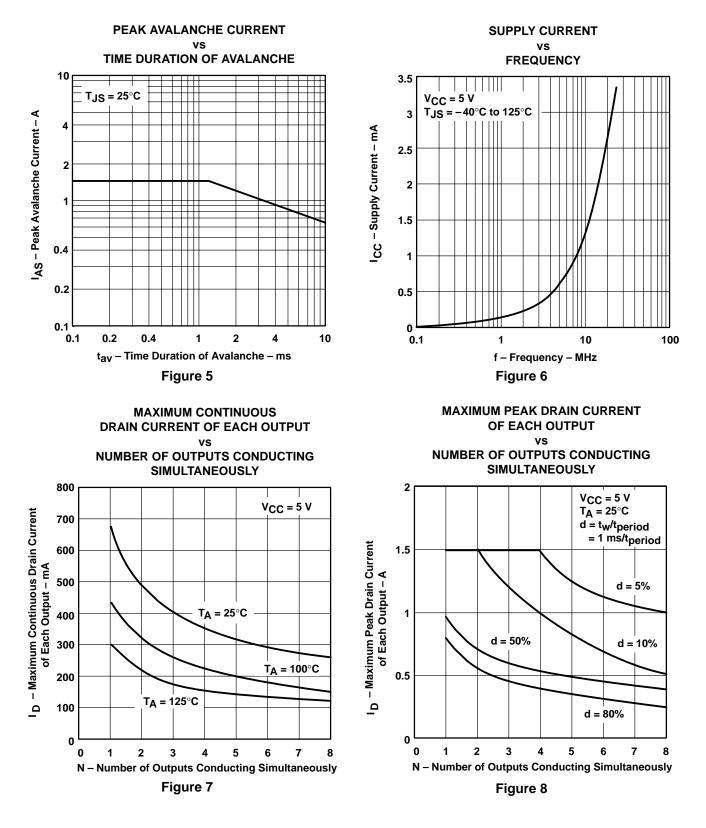
NOTES: A. The word generator has the following characteristics:  $t_f \le 10$  ns,  $t_f \le 10$  ns,  $Z_O = 50 \Omega$ . B. Input pulse duration,  $t_W$ , is increased until peak current  $I_{AS} = 1$  A. Energy test level is defined as  $E_{AS} = I_{AS} \times V_{(BR)DSX} \times t_{av}/2 = 75$  mJ, where  $t_{av}$  = avalanche time.

#### Figure 4. Single-Pulse Avalanche Energy Test Circuit and Waveforms



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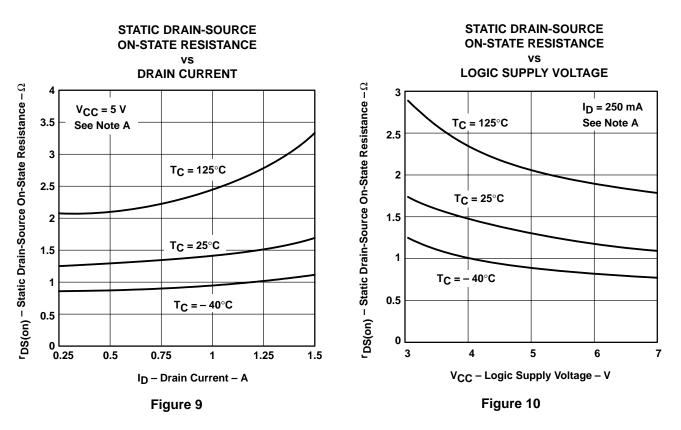
### **TYPICAL CHARACTERISTICS**

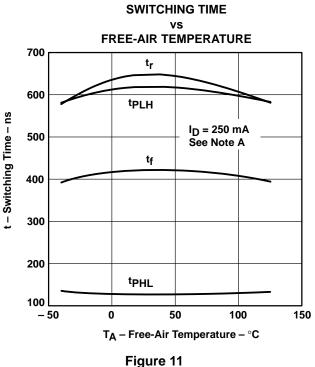




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NOTE A: Technique should limit  $T_J - T_C$  to 10°C maximum.



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